

Notice of References Cited	Application/Control No. 10/527,911	Applicant(s)/Patent Under Reexamination KNEE ET AL.	
	Examiner EUENG-NAN YEH	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,173,077	01-2001	Trew et al.	382/236
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Min et al.; "Progress in Automated Evaluation of Curved Surface Range Image Segmentation"; Sept 3-7, 2000, International Conference on Pattern Recognition; Vol. 1, pp. 644-647
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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